

**Search Notes**

Application/Control No.

10/572,982

Examiner

Chris C. Chu

Applicant(s)/Patent under  
Reexamination

DEKKER ET AL.

Art Unit

2815

**SEARCHED**

Class	Subclass	Date	Examiner
257	E23.008, E23.073 & E23.174	8/16/2007	C.C.
257	E23.193	8/16/2007	C.C.
257	E25.029	8/16/2007	C.C.
257	676 & 686	8/16/2007	C.C.
257	689 & 728	8/16/2007	C.C.
257	735	8/16/2007	C.C.
357	74 & 75	8/16/2007	C.C.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	8/16/2007	C.C.